Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/817,251	WILEY, LIEN L.
Examiner	Art Unit
Huyen Le	3751

	SEAR	CHED	
Class	Subclass	Date	Examiner
401	21 208	4/14/2006	HL
	210 216		
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	281 204		
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INTERFERENCE SEARCHED					
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